

**Notice of References Cited**Application/Control No.  
**09/819,946**Applicant(s)/Patent Under Reexam  
**Walke et al.**Examiner  
**Michael Brannock, Ph.D**Art Unit  
**1646**

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
	A					
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
X	N	WO 00/06592	2/2000	WO	ZUKER et al	---	---
	O						
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**NON-PATENT DOCUMENTS**

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	U	WO 00/06592, ZUKER et al., February 10, 2000: sequence alignment with 09819946-1
	V	Bowie et al., 1990, Science 247:1306-1310
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<sup>1</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.